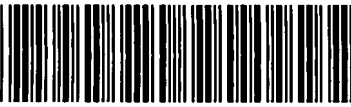
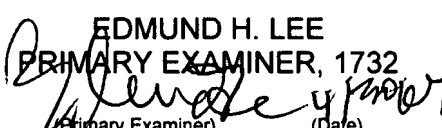
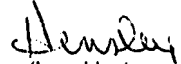


<b>Issue Classification</b> 	<b>Application/Control No.</b> 10/757,420	<b>Applicant(s)/Patent under Reexamination</b> YAMAKAWA ET AL.	
	<b>Examiner</b> EDMUND H. LEE	<b>Art Unit</b> 1732	

ISSUE CLASSIFICATION										
ORIGINAL					CROSS REFERENCE(S)					
CLASS		SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
264		161			264	162				
INTERNATIONAL CLASSIFICATION					83	13				
B	2	9	C	67/00						
				/						
				/						
				/						
				/						

(Assistant Examiner) (Date)		EDMUND H. LEE PRIMARY EXAMINER, 1732  (Primary Examiner) (Date)	Total Claims Allowed: 5	
 (Legal Instruments Examiner)	5-15-07 (Date)		O.G. Print Claim(s) 1	O.G. Print Fig. 1

<input checked="" type="checkbox"/> Claims renumbered in the same order as presented by applicant										<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
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